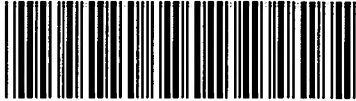


<b>Search Notes</b> 	<b>Application/Control No.</b> 10574110	<b>Applicant(s)/Patent Under Reexamination</b> HAYASHI, TOSHIO
	<b>Examiner</b> Cho, Jennifer Y	<b>Art Unit</b> 1621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	12/3/07	JC
Inventor Search	12/3/07	JC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner